

ı	Application/Co	ntrol No.

Examiner

JOHN J. LEE

10/044,408

Applicant(s)/Patent under Reexamination

OSTERKAMP, MARK ALAN

Art Unit

2618

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ORIGINAL						CROSS REFERENCE(S)								
CLASS SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)										
73				510	73	1.79	584	488						
INTERNATIONAL CLASSIFICATION				CLASSIFICATION	455	41.2	41.3							
G	0	1	Р	3/04										
Η	0	4	В	7/00										
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John J. Lee 3/2/2007 (Assistant Examiner) (Date) (Legal Instruments Examiner) (Date)					1		EDWARD F		Total Claims Allowed: 13					
					15/07	SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)				O. Print C	O.G. Print Fig.			
					Date)					,	16			

Claims renu	Claims renumbered in the same order as presented by applicant								☐ T.D.		☐ R.1.47	
Final	Final	Final		Final Original		Final	Original		Final	Original	Final	Original
1 1	31	61	1	91	1		121	İ		151		181
2 2	 32 .	62	7	92	1		122			152		182
3 3	- 33	63	7	93	1		123			153		183
4 4	- 34	64	7 -	94]		124	Ī		154		184
5 5	35	65	7	. 95	7		125			155		185
6	 36	66	1 [96	1		126			156		186
7	11 37	67	7	97	7		127			157		187
8	12 38	68		98			128			158	•	188
9	13 39	69] , [99			129	ſ		159		189
10	40	70	7	100	1		130			160		190
· 11	41	71	1 [101]		131	[161	,	191
6 12	42	72	1 [102]		132	[162		192
. 7 13	43	73	7	103	1 1		133	Ī		163		193
8 14	44	74	7 -	104	1		134	Ī		164		194
9 15	45	75	1	105	1		135	Ī		165		195
10 16	46	76	1	106	1		136			166		196
17	47	77		107			137			167		197
18	48	78		108			138			168		198
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20	50	80	1 [110	1 1		140			170		200
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22	52	82		112	1		142			172		202
23	53	83		113	1		143			173		203
24	54	84	7	114]		144			174		204
25	55	85	7	115]		145	Ī		175		205
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27	57	87	7	117	1		147	ľ		177		207
28	58	88	7	118	1		148			178		208
29	59	89	7	119	1		149	Ī		179		209
30	60	90		120	1		150			180		210